Supplementary Information (SI) for Journal of Analytical Atomic Spectrometry. This journal is © The Royal Society of Chemistry 2025

Supplementary Information

Detection and Quantification of Trace Technetium in the Presence of Molybdenum Using Laser-Induced Breakdown Spectroscopy

Hunter B. Andrews,^{1,*} Zachary Murphy,³ Mauro Martinez,^{2,‡} John Lucchi,²

Vasileios Anagnostopoulos,³ Matthieu Baudelet^{2,3,4,5,*}

¹Radioisotope Science and Technology Division, Oak Ridge National Laboratory, Oak Ridge, Tennessee, USA

²National Center of Forensic Science, University of Central Florida, Orlando, Florida, USA

³Chemistry Department, University of Central Florida, Orlando, Florida, USA

⁴CREOL—The College of Optics and Photonics, University of Central Florida, Orlando, Florida, USA

- ⁵ Anthropology Department, University of Central Florida, Orlando, Florida, USA
- [‡] Now at Department of Environmental Medicine and Public Health, Icahn School of Medicine at Mount Sinai, New York, New York, USA
- *Corresponding author: (H.B.A.) andrewshb@ornl.gov; (M.B.) baudelet@ucf.edu

Summary of contents:

- Sample preparation schematic
- Multichannel univariate calibration curves
- CZ ICCD univariate calibration curves
- Survey of Tc emissions at trace concentrations in Mo matrix
- Survey of concentrated Tc emissions on Si substrate

Notice: This manuscript has been authored in part by UT-Battelle, LLC, under contract DE-AC05-00OR22725 with the US Department of Energy (DOE). The US government retains and the publisher, by accepting the article for publication, acknowledges that the US government retains a nonexclusive, paid-up, irrevocable, worldwide license to publish or reproduce the published form of this manuscript, or allow others to do so, for US government purposes. DOE will provide public access to these results of federally sponsored research in accordance with the DOE Public Access Plan (http://energy.gov/downloads/doe-public-access-plan).

Sample Preparation and PVA Conversion

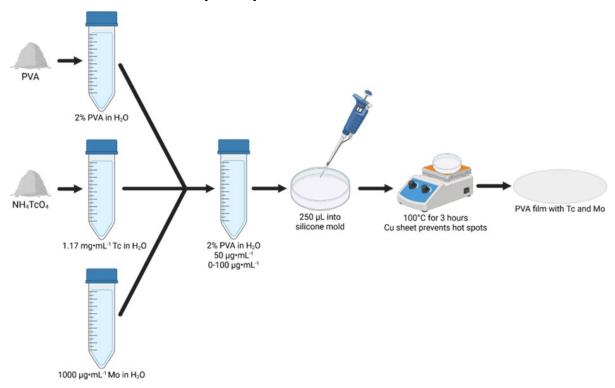


Figure S1. Diagram of the aqueous sample preparation and subsequent PVA film conversion.

Multichannel spectrometer Tc calibrations

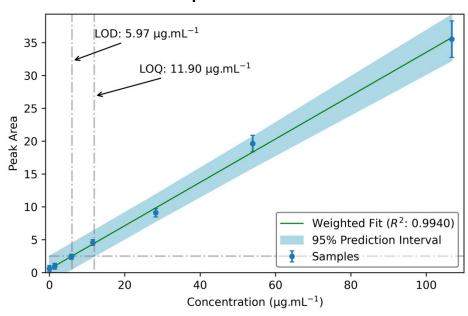


Figure S2. To calibration curve based on the 254.32 nm emission peak using the multichannel spectrometer.

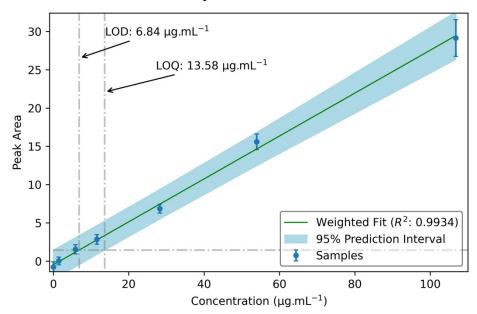


Figure S3. To calibration curve based on the 260.99 nm emission peak using the multichannel spectrometer.

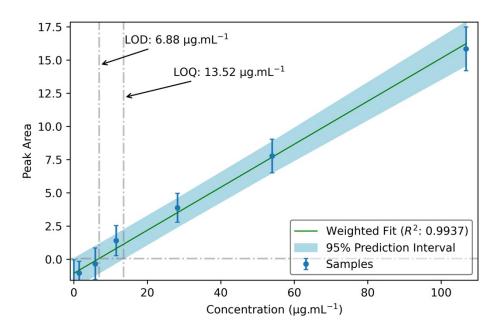


Figure S4. To calibration curve based on the 363.61 nm emission peak using the multichannel spectrometer.

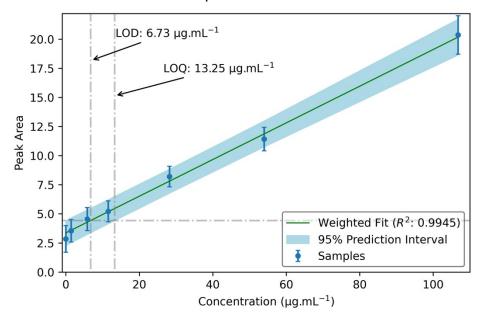


Figure S5. To calibration curve based on the 403.16 nm emission peak using the multichannel spectrometer.

CZ ICCD spectrometer Tc calibrations

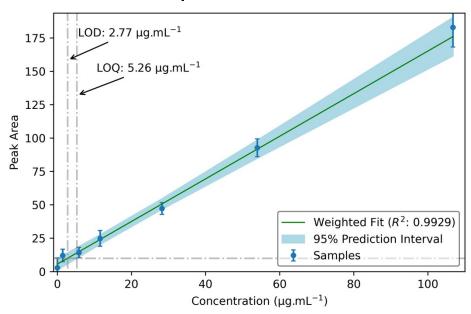


Figure S6. To calibration curve based on the 398.49 nm emission peak using the CZ ICCD spectrometer.

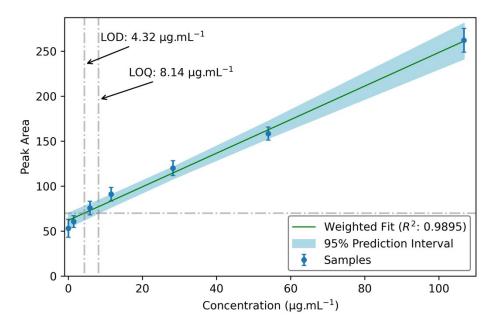


Figure S7. Tc calibration curve based on the 404.91 nm emission peak using the CZ ICCD spectrometer.

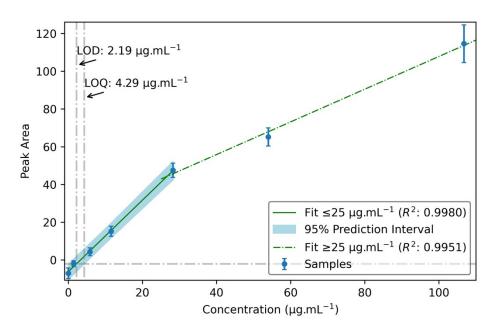


Figure S8. To calibration curve based on the 321.20 nm emission peak using the CZ ICCD spectrometer.

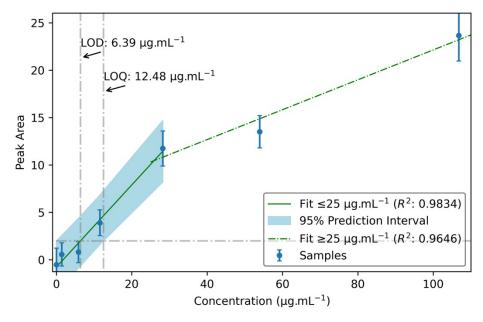
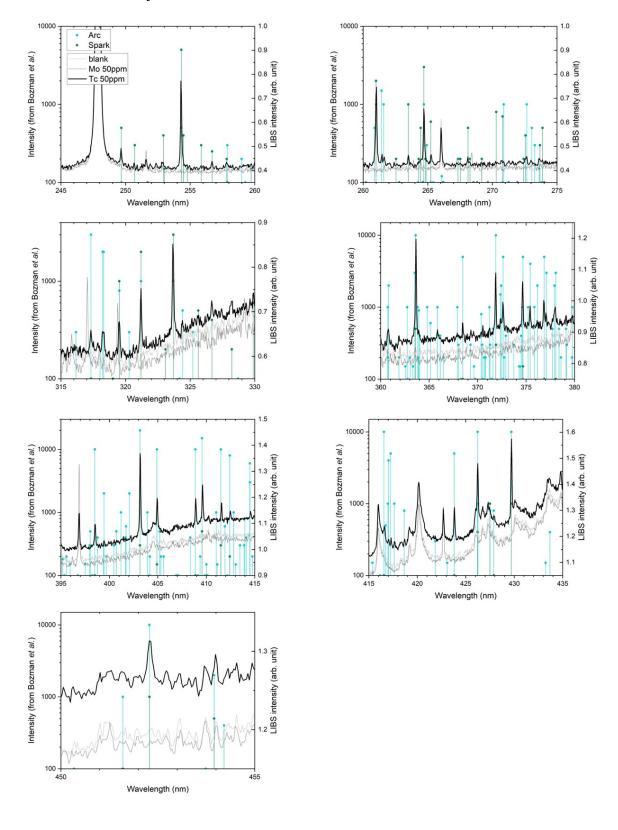


Figure S9. To calibration curve based on the 328.20 nm emission peak using the CZ ICCD spectrometer.

Survey of Tc emissions at trace concentrations in Mo matrix



Survey of concentrated Tc emissions on Si substrate

